

In the Abstract:

ABSTRACT OF THE DISCLOSURE

According to a method of measuring a thickness, to measure a thickness d of a liquid crystal layer $[[11]](11)$, a property of reflected light is utilized, in that the light returns maintaining the same polarizing plane as that of an entrance when a polarizing plane-maintaining condition is satisfied in which a difference in optical path lengths between an ordinary ray and an extraordinary ray of the reflected light is a sum of an integer multiple of the wavelength and a half-wavelength or an integer multiple, to find a wavelength at which the polarizing plane-maintaining condition is satisfied. A reasonable $\Delta n \cdot d$ is thereby found. This is performed for a plurality of wavelengths to find a relational expression of a wavelength and $\Delta n \cdot d$. A known combination of a wavelength λ and Δn is assigned to the relational expression to find d .